

MOS FIELD EFFECT TRANSISTOR **2SK3572**

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

The 2SK3572 is N-channel MOS FET device that features a low on-state resistance and excellent switching characteristics, designed for low voltage high current applications such as DC/DC converter with synchronous rectifier.

FEATURES

- 4.5 V drive available
- Low on-state resistance

 $R_{DS(on)1} = 5.7 \text{ m}\Omega \text{ MAX.} (V_{GS} = 10 \text{ V}, \text{ ID} = 40 \text{ A})$

Low gate charge

 $Q_G = 32 \text{ nC TYP}. (V_{DD} = 16 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 80 \text{ A})$

- Built-in gate protection diode
- Surface mount device available

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (VGs = 0 V)	Vdss	20	V
Gate to Source Voltage (VDS = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C)	D(DC)	±80	Α
Drain Current (pulse) Note	D(pulse)	±300	Α
Total Power Dissipation ($T_A = 25^{\circ}C$)	PT1	1.5	W
Total Power Dissipation (Tc = 25°C)	PT2	52	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	–55 to +150	°C
Note PW \leq 10 μ s, Duty Cycle \leq 1%			

★ ORDERING INFORMATION

PART NUMBER	PACKAGE
2SK3572	TO-220AB
2SK3572-S	TO-262
2SK3572-ZK	TO-263
2SK3572-Z	TO-220SMD Note

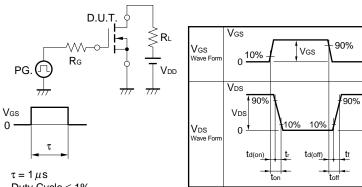
Note TO-220SMD package is produced only in Japan.

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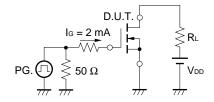
ELECTRICAL CHARACTERISTICS (TA = 25°C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	Vds = 20 V, Vgs = 0 V			10	μA
Gate Leakage Current	lgss	$V_{GS} = \pm 20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$			±10	μA
Gate Cut-off Voltage	V _{GS(off)}	$V_{DS} = 10 V, I_{D} = 1 mA$	1.5		2.5	V
Forward Transfer Admittance	y _{fs}	Vds = 10 V, Id = 40 A	15			S
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, Id = 40 A		4.4	5.7	mΩ
	RDS(on)2	Vgs = 4.5 V, Id = 40 A		7.4	9.9	mΩ
Input Capacitance	Ciss	V _{DS} = 10 V		1700		pF
Output Capacitance	Coss	V _{GS} = 0 V		700		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		250		pF
Turn-on Delay Time	td(on)	Vdd = 10 V, Id = 40 A		16		ns
Rise Time	tr	V _G s = 10 V		14		ns
Turn-off Delay Time	td(off)	Rg = 10 Ω		50		ns
Fall Time	tr			12		ns
Total Gate Charge	Q _G	Vdd = 16 V		32		nC
Gate to Source Charge	QGS	Vgs = 10 V		7.1		nC
Gate to Drain Charge	Qgd	ID = 80 A		7.7		nC
Body Diode Forward Voltage	VF(S-D)	IF = 80 A, VGS = 0 V		1.0		V
Reverse Recovery Time	trr	IF = 80 A, VGS = 0 V		42		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/µs		34		nC

TEST CIRCUIT 1 SWITCHING TIME

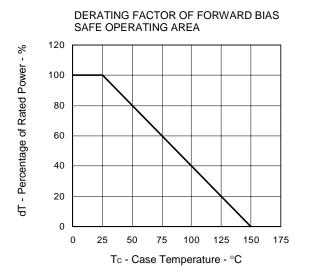


TEST CIRCUIT 2 GATE CHARGE

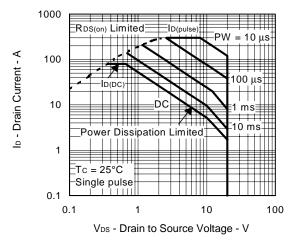


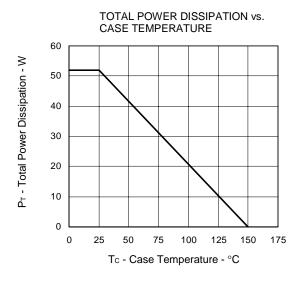
Duty Cycle $\leq 1\%$

TYPICAL CHARACTERISTICS (TA = 25^{\circ}C)

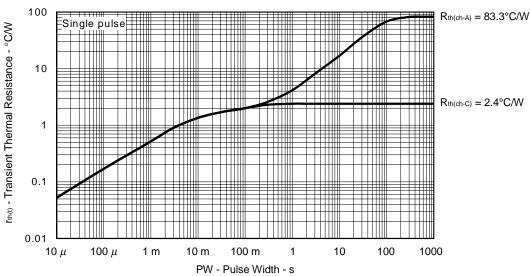


FORWARD BIAS SAFE OPERATING AREA





TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



3

2.5

2

1.5

1

0.5

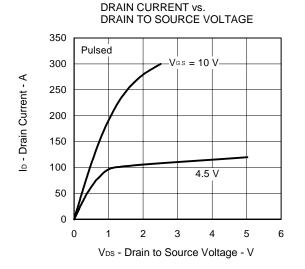
0

-50

0

V_{GS(off)} - Gate Cut-off Voltage - V





GATE CUT-OFF VOLTAGE vs.

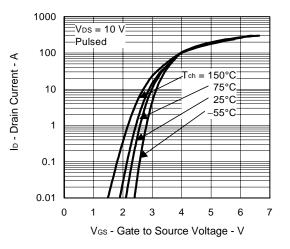
VDS = 10 V

 $-I_D = 1 \text{ mA}$

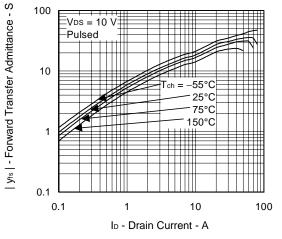
100

150

CHANNEL TEMPERATURE



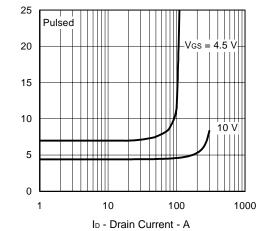
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



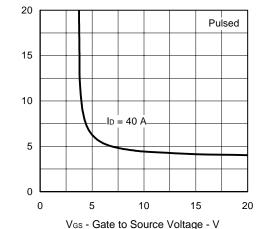


50

Tch - Channel Temperature - °C

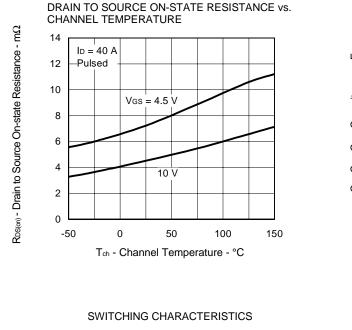


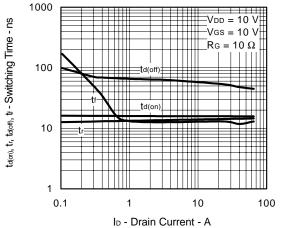
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



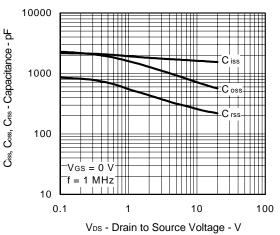
 $R^{\text{DS(on)}}$ - Drain to Source On-state Resistance - $m\Omega$

RDS(on) - Drain to Source On-state Resistance - mΩ

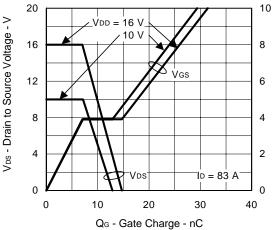




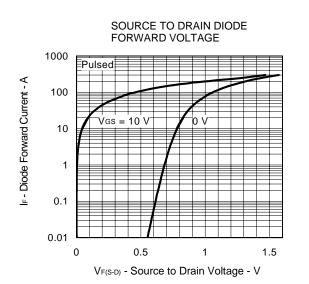




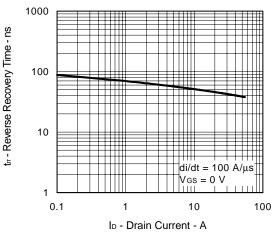
DYNAMIC INPUT/OUTPUT CHARACTERISTICS



Ves - Gate to Source Voltage - V



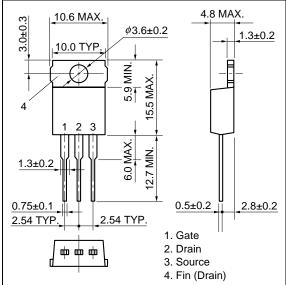
REVERSE RECOVERY TIME vs. DRAIN CURRENT



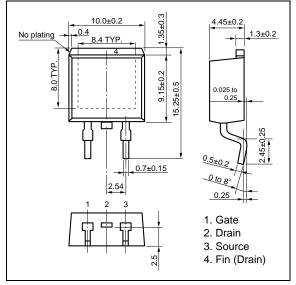
Data Sheet D16258EJ2V0DS

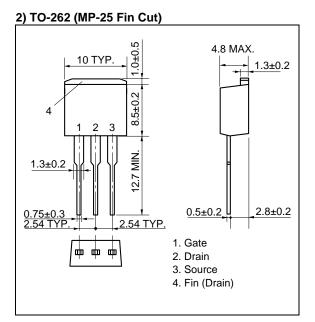
★ PACKAGE DRAWINGS (Unit: mm)

1) TO-220AB (MP-25)

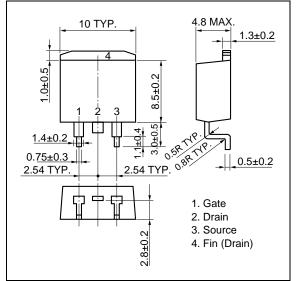


3) TO-263 (MP-25ZK)



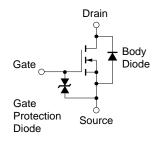


4) TO-220SMD (MP-25Z) Note



Note This package is produced only in Japan.

EQUIVALENT CIRCUIT



Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device. [MEMO]

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